Helios NanoLab DualBeam, which the AggieFab has recently acquired and being installed, has the following capabilities.

- Capable of adding/removing materials at nanometer scale
- Capable of preparing ultrathin samples for atomic scale analysis in TEM
- Achieve down to 0.5 nm resolution in SEM mode
- Achieve down to 4.0 nm resolution in FIB mode
- Integrated EasyLift nanomanipulator

An overview of this instrument’s capabilities, along with specific features will be introduced.

Schedule:
12—1 PM Seminar
1 PM - Meeting with Researchers
Register online at: https://goo.gl/forms/q7AQDrOjiLNVaxuh2

(Please contact admin@aggiefab.tamu.edu if you have any question)